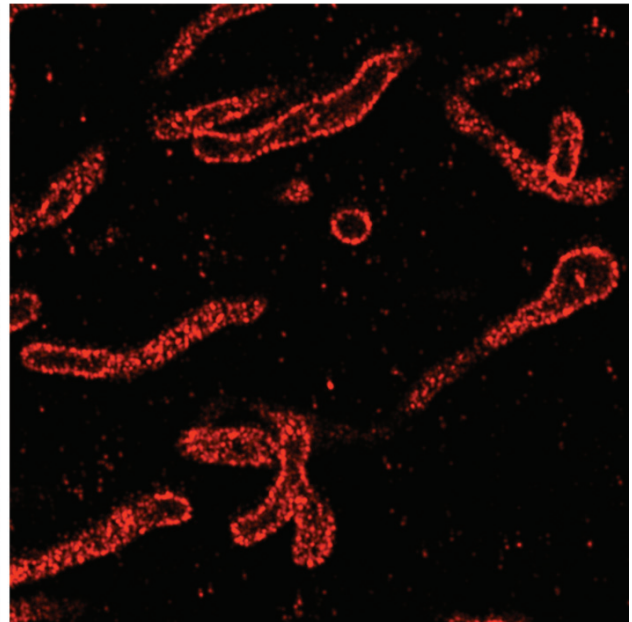
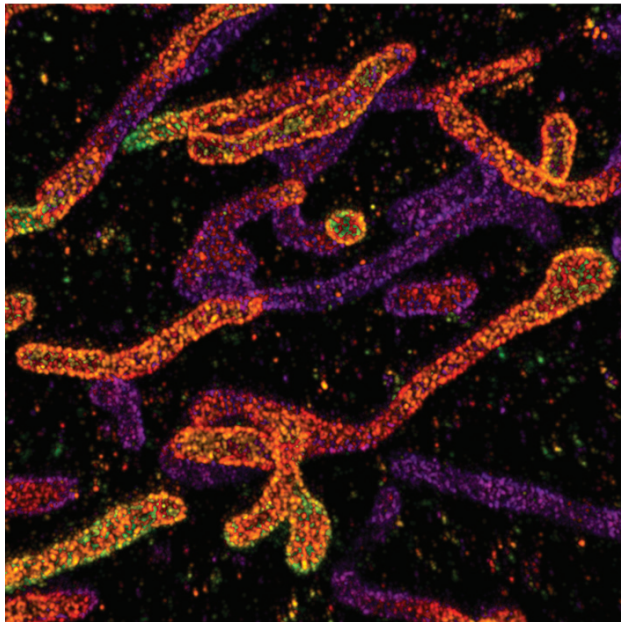
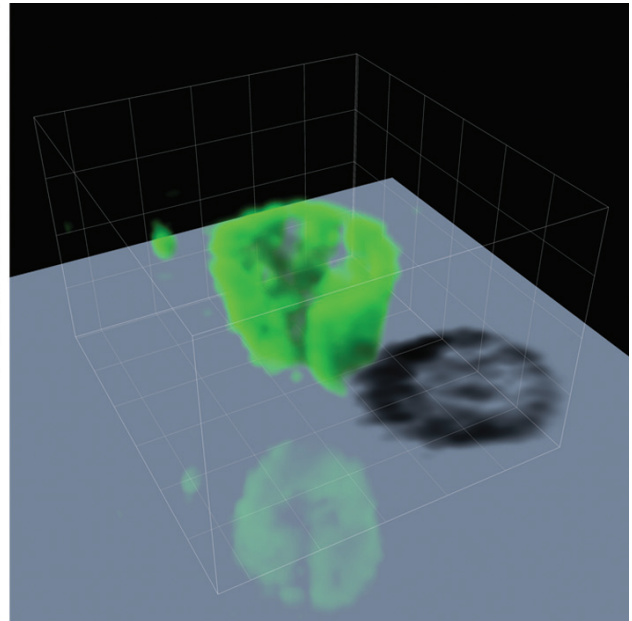
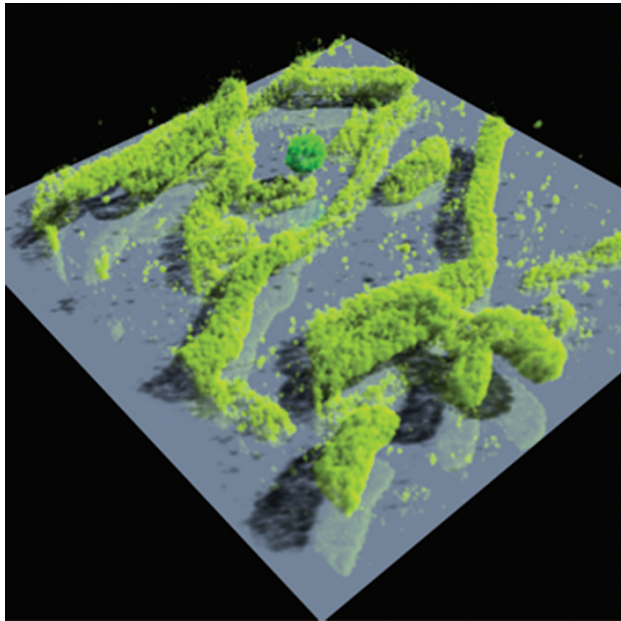


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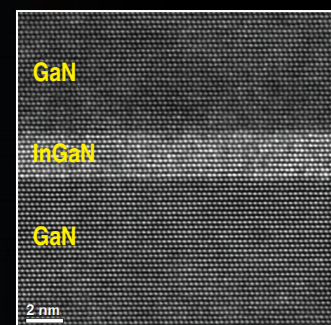
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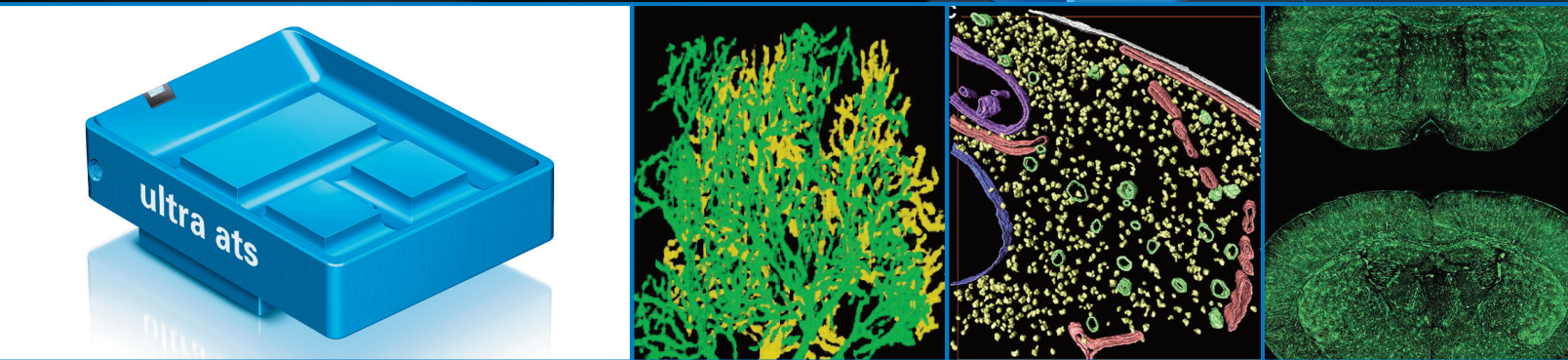


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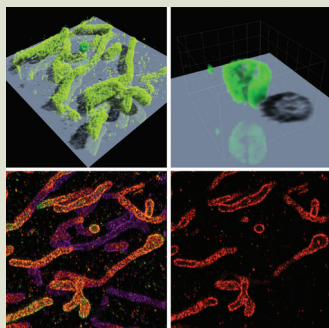
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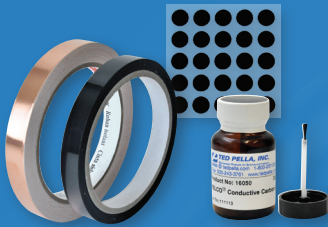
Super-resolution single molecule localization microscopy (SMLM) analysis using Huygens Localizer software. For details please see the article by Vermeer et al.

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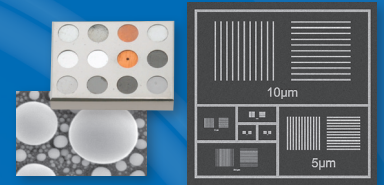
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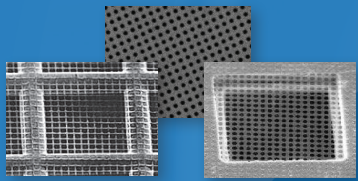
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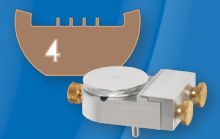
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